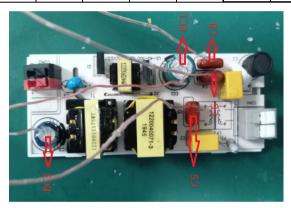


## **Temperature Rise Test Report**

<b>Product Inform</b>	nation												
Product:		LED Driver					Tester:						
Part No.:	LS-40-650 LI2					Test Date:			2020/7/17				
Ambient Temp.(°C):		25					Ambient humidity:				65.0%		
Data Record													
Driver Information:		Model: LS-40-650 LI2					Factory: Eaglerise Electric & Electric				ronic (China) Co., Ltd.		
Testing of component temperature rise at minimum operating voltage, rated operating voltage, maximum operating voltage, the test data shall include ambient temperature and 45°C data, and all data shall be tested in the final operating environment.  The external power supply is to be tested in a matching case, and the internal power supply is to be tested in a matching whole lamp. Also attached is a photo after temperature measurement and dispensing.													
Temp. in the Oven(°C)		25					45						
Input Voltage(V)		AC176V AC230V			AC264V		AC176V		AC230V		AC264V		
Component	Designation	Temp.	Δt	Temp.	∆t	Temp.	Δt	Temp.	Δt	Temp.	∆t	Temp.	∆t
Film capacitor	C5	57.5	32.5	56.7	31.7	57.7	32.7	77.2	32.2	76.3	31.3	77.3	32.3
Film capacitor	C6	58.9	33.9	56.7	31.7	56.6	31.6	78.5	33.5	76.5	31.5	76.2	31.2
Film capacitor	C8	56	31	54.1	29.1	54.1	29.1	75.8	30.8	74	29	73.8	28.8
Electrolytic capacitor	EC3	57.2	32.2	57	32	58.2	33.2	77	32	76.8	31.8	77.6	32.6
Electrolytic capacitor	EC1	57.7	32.7	56.5	31.5	56.9	31.9	77.4	32.4	76.1	31.1	76.5	31.5
	Max.	58.90	33.90	57.00	32.00	58.20	33.20	78.50	33.50	76.80	31.80	77.60	32.60



Item	Model Model	То	Rated Lifetime	Io	Ix	Actual temperature rise	△То	∆Тх	$L_{\mathrm{X(hrs)}}$	$L_{X(year)}$
Electrolysis EC3	150uf 50v 8*12	105	6000	130	123	77.8	5	3.00	52163	5.95
Electrolysis EC1	10uf 450v 10*16	105	6000	1950	1624	77.6	5	3.00	52891	6.04

Summary: At a ring temperature of 45°C, the life of the power supply is >50000H.								
Auditor _		Review Date	2020.7.20					

Life Estimation Formula for the Capacitors

$Lx = Lo \times 2$	(To-Tx)/10 ×	< 2 (△To-△Tx)/5	

 $L_X$ =lifetime(hours)of the capacitor to be estimated

 $L_o$ =Base (Assured)lifetime (hours)of the capacitor

 $T_o=Maximum\ rated\ operating\ temperature(^{\circ}C)$ 



bient temperature of the capacitor within device

(this is not the environment temperature of the device, but the environment temperature of the capacitor that has been placed within the device, details as note 2) 实际环境温度,  $\triangle T_0 = \text{Rise in core temperature of the capacitor due to rated (permissible)maximum ripple current.}$ 

 $\triangle$ Tx=Actual rise in the core temperature of the capacitor due to actual ripple current at device operating conditions.

 $\triangle Tx = \triangle To \times (Ix/Io)^{\triangle 2}$ 

Where: Io=rated rms ripple

Ix=Actual rms ripple